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FORM PTO-144 TRADEN S.S. DEPAR MENT TO OMMERCE PATENT AND TRADEMARK OFFICE (Modified)

DOCKET NO. **AWEK 2301**

APPLICATION NO. 09/941,485

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

FILING DATE

August 28, 2001

GROUP 1725

APPLICANT Mikko VEIKKOLAINEN et al

(37 CFR 1.98(b))

(Use several sheets If necessary)

		U.S. PAT	ENT DOCUMENTS								
EXAM INIT	PATENT NUMBER	ISSUE DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE					
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FOREIGN PATENT OR PUBLISHED FOREIGN PATENT APPLICATION											
EXAM INIT	DOCUMENT NUMBER	PUBL. DATE	COUNTRY OR PAT. OFFICE	CLASS	SUB CLASS	TRANS.					
INII		DATE	TAI. OTTIOE		02,100	Y	N				
4	1118297	03/1996	China								
4	101689	08/1998	Finland				. 7				
A	9061117	03/1997	Japan								
	OTHER DOCL	JMENTS (Including	g Author, Title, Date, Relevant Pages, Place	e of Publication)							
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EXAMINER: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



APPLICANT Mikko VEIKKOLAINEN et al

OCT 0 1 2002

FORM PTO-1449 (Modified)

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

DOCKET NO. AWEK 2301

APPLICATION NO. 09/941,485

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(Use several sheets if necessary)

FILING DATE

GROUP 1725

(37 CFR 1.98(b))

August 28, 2001

EXAM INIT	PATENT NUMBER	ISSUE DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE		
	5,572,102	11/1996	Goodfellow et al		-			
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EXAMINER: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.